

FCD820 • FCD820C

OPTICALLY-COUPLED ISOLATOR

OPTOELECTRONICS PRODUCT GROUP

GENERAL DESCRIPTION – The FCD820 series of optoisolators combines a gallium arsenide infrared emitting diode and a silicon npn phototransistor in close proximity. Optical intercoupling provides a high degree of ac and dc isolation. A capability for continuous operation of the input diode results in a frequency response extending to dc. Connection to the transistor base is also provided for design flexibility. The FCD820 is covered under U.L. component recognition program, reference file E55299.

- GLASSOLATED™
- HIGH CURRENT TRANSFER RATIO – TYPICALLY 50%
- 1500 V TO 6000 V MINIMUM ISOLATION INPUT-TO-OUTPUT
- 10^{11} Ω ISOLATION RESISTANCE
- LOW COUPLING CAPACITANCE – TYPICALLY 1.0 pF

ABSOLUTE MAXIMUM RATINGS

Storage Temperature	-55°C to +150°C
Operating Temperature	-55°C to +100°C
Pin Temperature (Soldering, 5 s)	260°C
Total Package Power Dissipation at $T_A = 25^\circ\text{C}$ (LED plus Detector)	250 mW
Derate Linearly from 25°C	3.3 mW/ $^\circ\text{C}$

INPUT DIODE

V_R	Reverse Voltage	3.0 V
I_F	Forward Current	60 mA
i_f	Peak Forward Current (1 μs pulse width, 300 pps)	3.0 A
P_D	Power Dissipation at $T_A = 25^\circ\text{C}$	100 mW
	Derate Linearly from 25°C	1.33 mW/ $^\circ\text{C}$

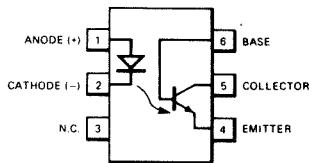
OUTPUT TRANSISTOR

V_{CE}	Collector to Emitter Voltage	30 V
V_{CB}	Collector to Base Voltage	70 V
I_C	Collector Current	25 mA
P_D	Power Dissipation at $T_A = 25^\circ\text{C}$	150 mW
	Derate Linearly from 25°C	2.0 mW/ $^\circ\text{C}$

ELECTRICAL CHARACTERISTICS – INPUT DIODE: $T_A = 25^\circ\text{C}$

SYMBOL	CHARACTERISTIC	MIN	TYP	MAX	UNITS	TEST CONDITIONS
V_F	Forward Voltage		1.2	1.5	V	$I_F = 60 \text{ mA}$
V_{BR}	Reverse Breakdown Voltage	3.0	8.0		V	$I_R = 10 \mu\text{A}$

CONNECTION DIAGRAM
DIP (TOP VIEW)



PIN NUMBERS

1 Anode (+)	Input Diode
2 Cathode (-)	
3 NC	
4 Emitter	
5 Collector	Output npn
6 Base	Phototransistor

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ELECTRICAL CHARACTERISTICS – OUTPUT TRANSISTOR: $T_A = 25^\circ\text{C}$

SYMBOL	CHARACTERISTIC	MIN	TYP	MAX	UNITS	TEST CONDITIONS
V_{CEO}	Collector-Emitter Voltage	30	65		V	$I_C = 1.0 \text{ mA}, I_F = 0$
V_{CBO}	Collector-Base Voltage	70	165		V	$I_C = 100 \mu\text{A}, I_F = 0$
I_{CEO}	Collector-Emitter Leakage Current			50	nA	$V_{CE} = 10 \text{ V}, I_F = 0$
I_{CBO}	Collector-Base Leakage Current			20	nA	$V_{CB} = 10 \text{ V}, I_F = 0$
h_{FE}	Forward Current Gain	100	250			$V_{CE} = 5.0 \text{ V}, I_C = 100 \mu\text{A}$
C_{cb}	Collector-Base Capacitance		20		pF	$V_{CB} = 10 \text{ V}$
C_{eb}	Emitter-Base Capacitance		10		pF	$V_{EB} = 0$

ELECTRICAL CHARACTERISTICS – COUPLED: $T_A = 25^\circ\text{C}$

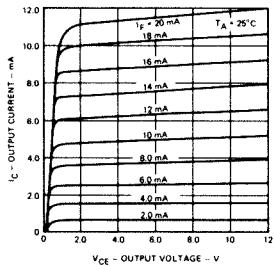
SYMBOL	CHARACTERISTIC	MIN	TYP	MAX	UNITS	TEST CONDITIONS
V_{IO}	Input-to-Output Voltage FCD820 FCD820C	1500 5000			V_{rms} V_{pk}	
$V_{CE(SAT)}$	Collector-Emitter Saturation Voltage		0.24	0.40	V	$I_C = 2.2 \text{ mA}, I_F = 15 \text{ mA}$ (FCD820, $I_C = 2.0 \text{ mA}, I_F = 10 \text{ mA}$)
$I_C/I_F(CTR)$	Collector Current Transfer Ratio (Note 1)	20	50		%	$V_{CE} = 10 \text{ V}, I_F = 10 \text{ mA}$ (FCD820, $V_{CE} = 0.4 \text{ V}$)
R_{IO} C_{IO} t_r, t_f	Input-to-Output Resistance Input-to-Output Capacitance Collector Rise and Fall Times (Note 2)	10^{11}	1.0 2.5		Ω pF μs	$V_{IO} = 500 \text{ V}$ $f = 1.0 \text{ MHz}$ $I_C = 2.0 \text{ mA}, V_{CE} = 10 \text{ V}, R_L = 100 \Omega$

NOTES:

1. Collector current transfer ratio is defined as the ratio of the collector current to the forward bias input current.
2. Rise time is defined as the time for the collector current to rise from 10% to 90% of peak value. Fall time is defined as the time required for the current to decrease from 90% to 10% of peak value.

TYPICAL ELECTRICAL CHARACTERISTIC CURVES

**LOW LEVEL TRANSFER
CHARACTERISTICS**



**MAXIMUM POWER
DISSIPATION RATING VERSUS
AMBIENT TEMPERATURE**

